



PCTEST ENGINEERING LABORATORY, INC.

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MEASUREMENT REPORT FCC Part 15B

Applicant Name:

Samsung Electronics, Co. Ltd.
18600 Broadwick St.
Rancho Dominguez, CA 90220
United States

Date of Testing:

October 19 - 24, 2011

Test Site/Location:

PCTEST Lab, Columbia, MD, USA

Test Report Serial No.:

0Y1110171830.A3L

FCC ID: A3LSCHW999

APPLICANT: Samsung Electronics, Co. Ltd.

Application Type:

Certification

EUT Type:

Portable Handset

Model(s):

SCH-W999

FCC Rule Part(s):

FCC Part 15 Subpart B

FCC Classification:

FCC Class B Digital Device (JBP)

Test Procedure:

ANSI C63.4-2003

The device bearing the FCC Identifier specified above has been shown to comply with the applicable technical standards as indicated in the measurement report and has been tested in accordance with the measurement procedures specified in ANSI C63.4-2003 (See Test Report). The results shown herein are also deemed satisfactory evidence of compliance with Industry Canada Interference-Causing Equipment Standard ICES-003. These measurements were performed with no deviation from the standards. Test results reported herein relate only to the item(s) tested.

I authorize and attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

NVLAP accreditation does not constitute any product endorsement by NVLAP or any agency of the United States Government. This report must not be used by the customer to claim product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government. PCTEST certifies that no party to this application has been subject to a denial of Federal benefits that includes FCC benefits pursuant to Section 5301 of the Anti-Drug Abuse Act of 1988, 21 U.S.C. 862.


Randy Ortanez
President

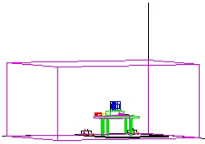
NVLAP[®]
Lab Code 100431-0

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 1 of 20

T A B L E O F C O N T E N T S

FCC Class B MEASUREMENT REPORT	3
1.0 INTRODUCTION	4
1.1 SCOPE	4
1.2 PCTEST TEST LOCATION	4
2.0 PRODUCT INFORMATION.....	5
2.1 EQUIPMENT DESCRIPTION	5
2.2 DEVICE CAPABILITIES	5
2.3 OPERATION MODE.....	5
2.4 EMI SUPPRESSION DEVICE(S)/MODIFICATIONS	5
2.5 LABELING REQUIREMENTS	5
3.0 DESCRIPTION OF TEST	6
3.1 EVALUATION PROCEDURE	6
3.2 CONDUCTED EMISSIONS.....	6
3.3 RADIATED EMISSIONS.....	7
4.0 SAMPLE CALCULATIONS	8
4.1 CONDUCTED EMISSION MEASUREMENT SAMPLE CALCULATION	8
4.2 RADIATED EMISSION MEASUREMENT SAMPLE CALCULATION.....	8
5.0 TEST EQUIPMENT CALIBRATION DATA	9
6.0 ENVIRONMENTAL CONDITIONS	10
7.0 TEST DATA	11
7.1 SUMMARY	11
7.2 TEST SUPPORT EQUIPMENT	11
7.3 RADIATED MEASUREMENT DATA	12
7.4 LINE CONDUCTED MEASUREMENT DATA	13
8.0 CONCLUSION.....	15
9.0 TEST SETUP PHOTOGRAPHS	16
10.0 EUT PHOTOGRAPHS	19

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 2 of 20



MEASUREMENT REPORT

FCC Part 15B – Unintentional Radiators



§ 2.1033 General Information

APPLICANT: Samsung Electronics, Co. Ltd.

APPLICANT ADDRESS: 18600 Broadwick St.
Rancho Dominguez, CA 90220

TEST SITE: PCTEST ENGINEERING LABORATORY, INC.

TEST SITE ADDRESS: 6660-B Dobbin Road, Columbia, MD 21045 USA

FCC RULE PART(S): FCC Part 15 Subpart B

FCC ID: A3LSCHW999

Test Device Serial No.: FI-254-C ☐ Production ☒ Pre-Production ☐ Engineering

FCC CLASSIFICATION: FCC Class B Digital Device (JBP)

DATE(S) OF TEST: October 19 - 24, 2011

Test Methodology

Both conducted and radiated measurements were taken using the methods and procedures described in ANSI C63.4-2003. Radiated testing was performed at an antenna-to-EUT distance of 3 meters.

Test Facility / NVLAP Accreditation

Conducted and radiated tests were performed at PCTEST Engineering Lab in Columbia, MD 21045, U.S.A.

- PCTEST facility is an FCC registered (PCTEST Reg. No. 90864) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (2451A-1).
- PCTEST Lab is accredited by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP) in EMC, Telecommunication, and FCC for satisfactory compliance with criteria established in Title 15, Part 285 Code of Federal Regulations. (NVLAP Lab code: 100431-0).
- PCTEST Lab is a recognized U.S. Conformity Assessment Body (CAB) in EMC and R&TTE (n.b. 0982) under the U.S.-EU Mutual Recognition Agreement (MRA).
- PCTEST TCB is a Telecommunication Certification Body (TCB) accredited to ISO/IEC Guide 65 by the American National Standards Institute (ANSI) in all scopes of FCC Rules and Industry Canada Standards (RSS).
- PCTEST facility is an IC registered (2451A-1) test laboratory with the site description on file at Industry Canada.

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 3 of 20

1.0 INTRODUCTION

1.1 Scope

Measurement and determination of electromagnetic emissions (EMC) of radio frequency devices including intentional and/or unintentional radiators for compliance with the technical rules and regulations of the Federal Communications Commission and the Industry Canada Certification and Engineering Bureau.

1.2 PCTEST Test Location

The map below shows the location of the PCTEST LABORATORY, its proximity to the FCC Laboratory, the Columbia vicinity area, the Baltimore-Washington Internt'l (BWI) airport, the city of Baltimore and the Washington, DC area. (see Figure 1-1).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility in New Concept Business Park, Guilford Industrial Park, Columbia, Maryland. The site address is 6660-B Dobbin Road, Columbia, MD 21045. The test site is one of the highest points in the Columbia area with an elevation of 390 feet above mean sea level. The site coordinates are 39° 11'15" N latitude and 76° 49'38" W longitude. The facility is 1.5 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. There are no FM or TV transmitters within 15 miles of the site. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4-2003 on January 28, 2009.

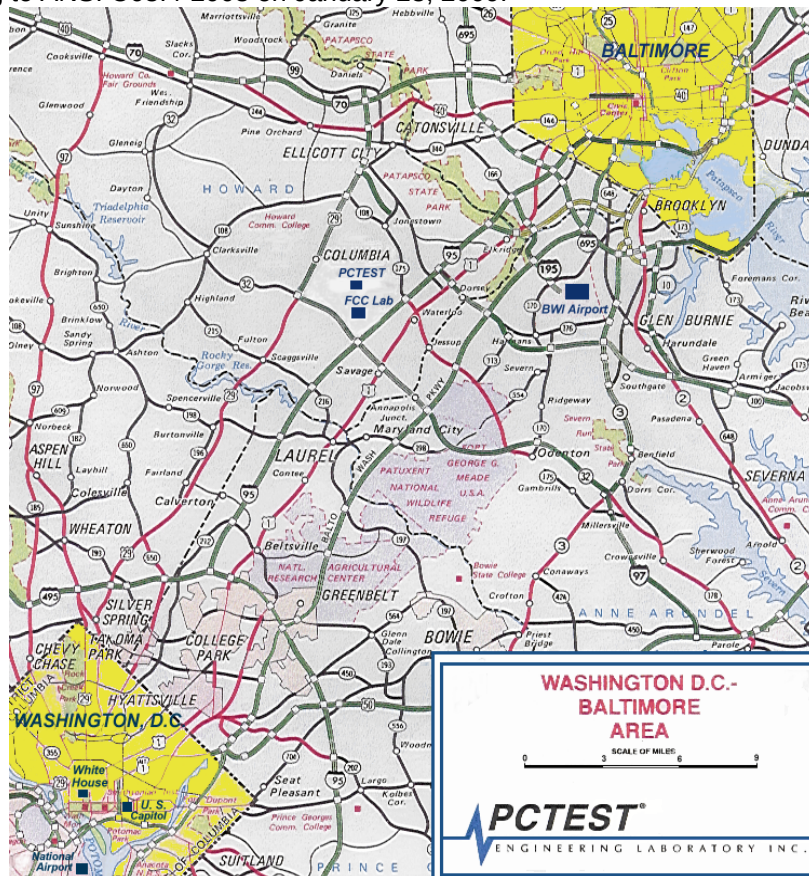


Figure 1-1. Map of the Greater Baltimore and Metropolitan Washington, D.C. area

FCC ID: A3LSCHW999	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 4 of 20

2.0 PRODUCT INFORMATION

2.1 Equipment Description

The Equipment Under Test (EUT) is the **Samsung Portable Handset FCC ID: A3LSCHW999**. The test data contained in this report pertains only to the emissions due to the digital circuitry of the EUT.

Manufacturer / Base Model	FCC ID	Description
Samsung / Model: SCH-W999	A3LSCHW999	Portable Handset

Table 2-1. EUT Equipment Description

2.2 Device Capabilities

This device contains the following capabilities:

850/1900 CDMA/EvDO (BC0, BC1), 1900 GSM/GPRS/EDGE, 802.11a/b/g/n WLAN, 802.11a/n UNII, Bluetooth

2.3 Operation Mode

The Samsung Portable Handset FCC ID: A3LSCHW999 was tested with a NOTEBOOK connected via USB interface port. The EUT was exercised during testing by means of software installed on the notebook. For more information please see Section 7.0 for test data and Sections 9.0 and 10.0 for the test setup photographs.

2.4 EMI Suppression Device(s)/Modifications

No EMI suppression device(s) were added and no modifications were made during testing.

2.5 Labeling Requirements

Per 15.19; Docket 95-19

The label shall be permanently affixed at a conspicuous location on the device; instruction manual or pamphlet supplied to the user and be readily visible to the purchaser at the time of purchase. However, when the device is so small wherein placement of the label with specified statement is not practical, only the trade name and FCC ID must be displayed on the device per Section 15.19(b)(2).

Please see attachment for FCC ID label and label location.

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 5 of 20

3.0 DESCRIPTION OF TEST

3.1 Evaluation Procedure

The measurement procedure described in the American National Standard for Methods of Measurement of Radio-Noise Emission from Low-Voltage Electrical and Electronic Equipment in the Range of 9kHz to 40GHz (ANSI C63.4-2003) was used in the measurement of the **Samsung Portable Handset** FCC ID: A3LSCHW999.

Deviation from measurement procedure.....None

3.2 Conducted Emissions

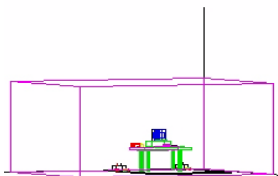


Figure 3-1. Shielded Enclosure Line-Conducted Test Facility

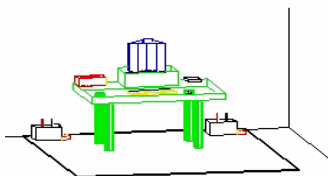


Figure 3-2. Line Conducted Emission Test Set-Up

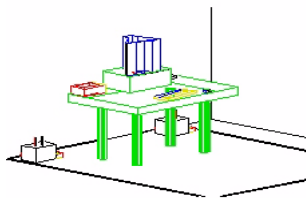


Figure 3-3. Wooden Table & Bonded LISNs

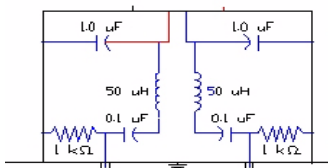


Figure 3-4. LISN Schematic Diagram

The line-conducted facility is located inside a 16'x20'x10' shielded enclosure, manufactured by Ray Proof Series 81 (see Figure 3-1). The shielding effectiveness of the shielded room is in accordance with MIL-Std-285 or NSA 65-5. A 1m x 1.5m wooden table 80cm high is placed 40cm away from the vertical wall and 1.5m away from the sidewall of the shielded room (see Figure 3-2). Solar Electronics and EMCO Model 3725/2 (10kHz-30MHz) 50Ω/50μH Line-Impedance Stabilization Networks (LISNs) are bonded to the shielded room (see Figure 3-3). The EUT is powered from the Solar LISN and the support equipment is powered from the EMCO LISN. Power to the LISNs are filtered by a high-current high-insertion loss Ray Proof power line filter (100dB 14Hz-10GHz). The purpose of the filter is to attenuate ambient signal interference and this filter is also bonded to the shielded enclosure. All electrical cables are shielded by braided tinned copper zipper tubing with an inner diameter of ½". If the EUT is a DC-powered device, power will be derived from the source power supply it normally will be powered from and this supply line(s) will be connected to the Solar LISN. The LISN schematic diagram is shown (see Figure 3-4). All interconnecting cables more than 1 meter were shortened to a 1 meter length by non-inductive bundling (serpentine fashion). Sufficient time for the EUT, support equipment, and test equipment was allowed in order for them to warm up to their normal operating condition. The RF output of the LISN was connected to the spectrum analyzer to determine the frequency producing the maximum EME from the EUT.

The spectrum was scanned from 150kHz to 30MHz with a spectrum analyzer. The detector function was set to CISPR quasi-peak and average mode. The bandwidth of the analyzer was set to 10kHz. The EUT, support equipment, and interconnecting cables were arranged and manipulated to maximize each EME emission. Each emission was maximized by: switching power lines; varying the mode of operation or resolution; clock or data exchange speed; scrolling H pattern to the EUT and/or support equipment, and powering the monitor from the floor mounted outlet box and the computer aux AC outlet, if applicable; whichever determined the worst-case emission. Photographs of the worst-case emission can be seen in the test setup photographs. Each EME reported was calibrated using the Agilent E8257D (250kHz – 20GHz) PSG Signal Generator.

FCC ID: A3LSCHW999	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 6 of 20

4.0 SAMPLE CALCULATIONS

4.1 Conducted Emission Measurement Sample Calculation

@ 20.3 MHz

Class B limit = 60.0 dB μ V (Quasi-peak limit)
Reading = - 57.8 dBm (calibrated quasi-peak level)
Convert to dB μ V = - 57.8 + 107 = 49.2 dB μ V

Margin = 49.2 - 60.0 = - 10.8 dB
= 10.8 dB below limit

4.2 Radiated Emission Measurement Sample Calculation

@ 66.7 MHz

Class B limit = 100 μ V/m = 40.0 dB μ V/m
Reading = - 76.0 dBm (calibrated level)
Convert to dB μ V = - 76.0 + 107 = 31.0 dB μ V
Antenna Factor + Cable Loss = 5.8 dB/m
Total = 36.8 dB μ V/m

Margin = 36.8 - 40.0 = - 3.2 dB
= 3.2 dB below limit

Note:

$$\text{Level [dB}\mu\text{V]} = 20 \log_{10} (\text{Level } [\mu\text{V/m}])$$
$$\text{Level [dB}\mu\text{V]} = \text{Level [dBm]} + 107$$

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 8 of 20

5.0 TEST EQUIPMENT CALIBRATION DATA

Test Equipment Calibration is traceable to the National Institute of Standards and Technology (NIST).

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
-	No.166	(1000-26500MHz) Microwave RF Cable	N/A		N/A	N/A
-	No.167	(100kHz - 100MHz) RG58 Coax Cable	N/A		N/A	N/A
Agilent	8447D	Broadband Amplifier	3/17/2011	Annual	3/17/2012	1937A03348
Agilent	8447D	Broadband Amplifier	3/17/2011	Annual	3/17/2012	2443A01900
Agilent	8449B	(1-26.5GHz) Pre-Amplifier	2/8/2011	Annual	2/8/2012	3008A00985
Agilent	85650A	Quasi-Peak Adapter	4/7/2011	Annual	4/7/2012	3303A01872
Agilent	85650A	Quasi-Peak Adapter	4/7/2011	Annual	4/7/2012	2043A00301
Agilent	8566B	(100Hz-22GHz) Spectrum Analyzer	4/7/2011	Annual	4/7/2012	2618A02866
Agilent	8566B	(100Hz-22GHz) Spectrum Analyzer	4/7/2011	Annual	4/7/2012	2542A11898
Agilent	8566B	(100Hz-22GHz) Spectrum Analyzer	4/7/2011	Annual	4/7/2012	3638A08713
Agilent	E4407B	ESA Spectrum Analyzer	4/5/2011	Annual	4/5/2012	US39210313
Agilent	E4448A	PSA (3Hz-50GHz) Spectrum Analyzer	11/30/2010	Annual	11/30/2011	US42510244
Agilent	E8257D	(250kHz-20GHz) Signal Generator	4/8/2011	Annual	4/8/2012	MY45470194
Agilent	N9038A	MXE EMI Receiver	8/5/2011	Annual	8/5/2012	MY51210133
Compliance Design	Roberts	Dipole Set	4/7/2010	Biennial	4/7/2012	146
Compliance Design	Roberts	Dipole Set	4/7/2010	Biennial	4/7/2012	147
Emco	6502	Active Loop Antenna (10k - 30 MHz)	4/8/2010	Biennial	4/8/2012	267
Emco	3816/2	LISN	11/5/2010	Biennial	11/5/2012	9707-1077
Emco	3816/2	LISN	11/3/2010	Biennial	11/3/2012	9707-1079
Pasternack	PE7000-6	6 dB Attenuator	N/A		N/A	N/A
Sunol	JB5	Bi-Log Antenna (30M - 5GHz)	12/17/2009	Biennial	12/17/2011	A051107
Sunol	DRH-118	Horn Antenna (1-18 GHz)	6/17/2011	Biennial	6/17/2013	A042511

Table 5-1. Annual Test Equipment Calibration Schedule

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 9 of 20

6.0 ENVIRONMENTAL CONDITIONS

The temperature is controlled within range of 15°C to 35°C.

The relative humidity is controlled within range of 10% to 75%.

The atmospheric pressure is controlled within the range 86-106kPa (860-1060mbar).

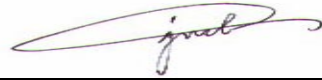
FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 10 of 20

7.0 TEST DATA

7.1 Summary

Test Date(s): October 19 - 24, 2011

Test Engineer:



FCC Part 15 Section	Description	Result
15.107	Conducted Emissions	PASS
15.109	Radiated Emissions	PASS

Table 7-1. Summary of Test Results

7.2 Test Support Equipment

1	Samsung Data Cable	Model: APCBU20BBC 1.2m Shielded USB Data Cable	S/N: RT1ZB08JS E
2	Panasonic Toughbook #2 w/ Panasonic AC Adapter	FCC ID: ACJ9TGCF-513 Model: CF-AA1683A 2.0m Unshielded AC power cord 2.0m Unshielded DC power cord with ferrite bead on notebook end	S/N: 7ATYA28277R S/N: 1683AM306Y01583D
3	Dynex USB PC Camera	Model: DX-WC101 (DoC) 2.07m Shielded USB Cable	S/N: 122D05AC

Note: See test setup photographs for actual system test setup.

7.3 Radiated Measurement Data

§15.109; RSS-Gen (6(a))

Frequency [MHz]	Level [dBm]	AFCL [dB]	Pol [H/V]	Height [m]	Azimuth [degrees]	Field Strength [dB μ V/m]	Limit [dB μ V/m]	Margin [dB]
46.49	-89.03	10.87	V	1.3	165	28.85	40.00	-11.15
221.09	-91.78	14.26	V	1.3	125	29.49	46.02	-16.53
240.49	-89.24	14.03	V	1.1	310	31.78	46.02	-14.24
294.81	-89.96	15.94	V	1.2	235	32.98	46.02	-13.04
720.64	-90.91	24.27	V	1.3	160	40.36	46.02	-5.66
741.01	-93.39	24.53	V	1.1	150	38.13	46.02	-7.89

Table 7-2. Radiated Measurements at 3-meters

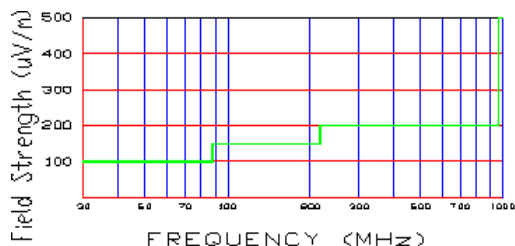


Figure 7-1. 3 Meter Limits

NOTES:

1. All modes of operation were investigated and the worst-case emissions are reported.
2. Radiated Emissions were measured from 30MHz – 2000MHz.
3. The radiated limits are shown on Figure 7-1. Above 960MHz the limit is 500 μ V/m.

1. All readings are calibrated by Agilent E8257D (250kHz – 20GHz) PSG Signal Generator with accuracy traceable to the National Institute of Standards and Technology (NIST).
2. AFCL = Antenna Factor and Cable Loss
3. Measurements made using CISPR quasi-peak mode. Above 1GHz, peak detector function mode is used with a resolution bandwidth of 1MHz and a video bandwidth of 1MHz. The peak level complies with the average limit. Peak mode is used with linearly polarized horn antenna and low-loss microwave cable.

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 12 of 20

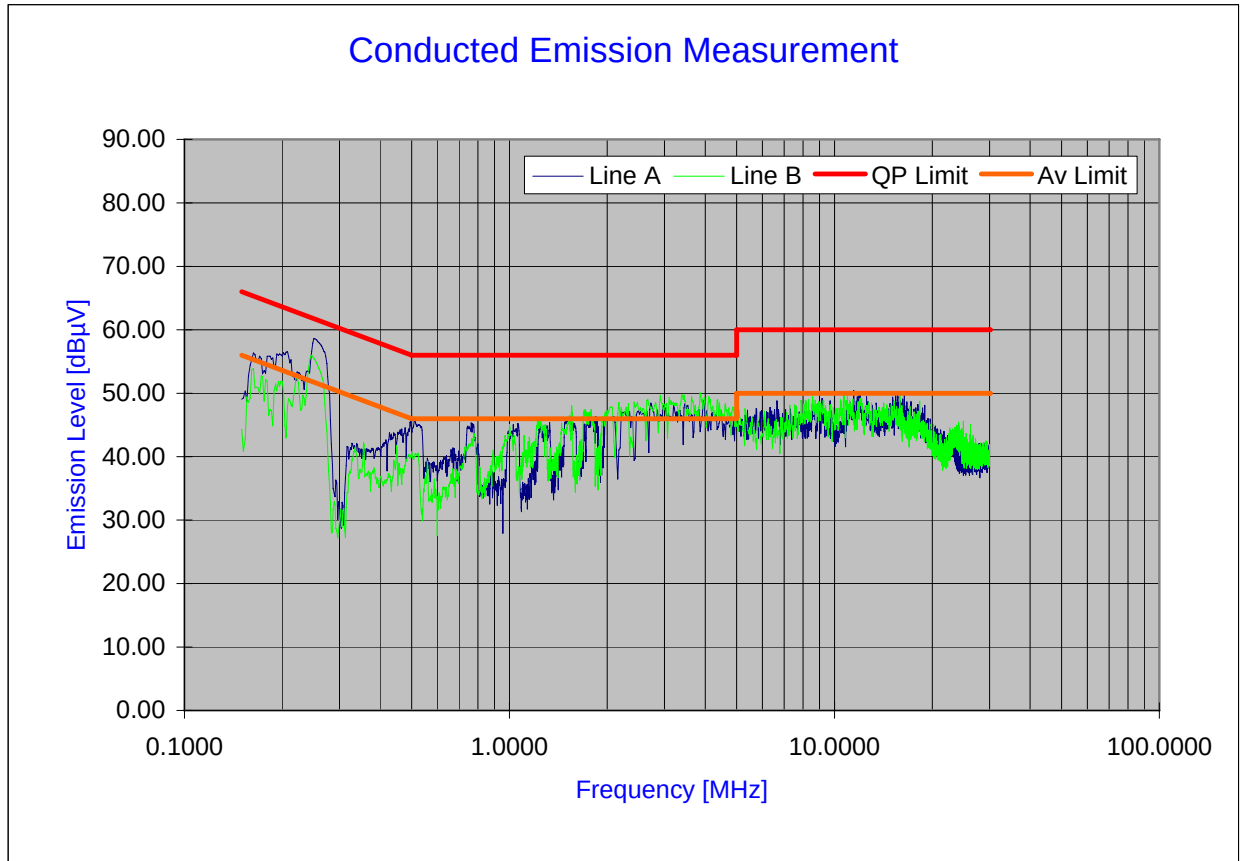
7.4 Line Conducted Measurement Data

§15.107; RSS-Gen (7.2.2)

PCTEST Engineering Laboratory Inc.

Company : Samsung Electronics, Co. Ltd.
Model Number : SCH-W999
FCC ID Code : A3LSCHW999

Power Source : AC120V/60Hz
Tested Date : 10/19/2011
Standard : FCC Part 15B class B



Plot 7-1. Line-Conducted Test Plot

Notes:

1. All Modes of operation were investigated and the worst-case emissions are reported.
2. The limit for Class B device(s) from 150kHz to 30MHz are specified in Section 15.107 of the Title 47 CFR.
3. Line A = Phase; Line B = Neutral
4. Traces shown in plot are made using a peak detector.
5. Deviations to the Specifications: None.

FCC ID: A3LSCHW999	PCTEST ENGINEERING LABORATORY, INC.	FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)	SAMSUNG	Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 13 of 20

Line Conducted Measurement Data (Cont'd)

§15.107; RSS-Gen (7.2.2)

No.	Line	Frequency [MHz]	Factor [dB]	QP [dBμV]	Limit [dBμV]	Margin [dB]	Average [dBμV]	Limit [dBμV]	Margin [dB]
1	A	0.249	6.89	57.18	61.79	-4.61	45.59	51.79	-6.20
2	A	1.965	7.15	44.34	56.00	-11.66	26.01	46.00	-19.99
3	A	2.203	7.18	44.89	56.00	-11.11	26.62	46.00	-19.38
4	A	2.699	7.24	45.53	56.00	-10.47	29.42	46.00	-16.58
5	A	2.703	7.24	45.33	56.00	-10.67	29.26	46.00	-16.74
6	A	3.437	7.30	45.40	56.00	-10.60	30.14	46.00	-15.86
7	A	3.779	7.33	41.63	56.00	-14.37	26.53	46.00	-19.47
8	A	3.935	7.34	45.08	56.00	-10.92	30.30	46.00	-15.70
9	A	4.415	7.37	44.10	56.00	-11.90	30.37	46.00	-15.63
10	A	11.537	7.73	41.58	60.00	-18.42	33.66	50.00	-16.34
11	B	0.244	6.89	54.60	61.98	-7.38	43.82	51.98	-8.16
12	B	2.399	7.21	45.51	56.00	-10.49	30.42	46.00	-15.58
13	B	2.641	7.23	46.13	56.00	-9.87	29.17	46.00	-16.83
14	B	2.877	7.26	46.51	56.00	-9.49	30.04	46.00	-15.96
15	B	2.890	7.26	46.66	56.00	-9.34	26.47	46.00	-19.53
16	B	3.131	7.28	46.22	56.00	-9.78	29.49	46.00	-16.51
17	B	3.858	7.35	46.24	56.00	-9.76	31.63	46.00	-14.37
18	B	4.104	7.37	45.93	56.00	-10.07	31.22	46.00	-14.78
19	B	4.313	7.38	45.55	56.00	-10.45	30.80	46.00	-15.20
20	B	4.552	7.40	45.11	56.00	-10.89	30.94	46.00	-15.06

Table 7-3. Line-Conducted Test Data

Notes:

1. All Modes of operation were investigated and the worst-case emissions are reported.
2. The limit for Class B device(s) from 150kHz to 30MHz are specified in Section 15.107 of the Title 47 CFR.
3. Line A = Phase; Line B = Neutral
4. Traces shown in plot are made using a peak detector.
5. Deviations to the Specifications: None.

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 14 of 20

8.0 CONCLUSION

The data collected relate only to the item(s) tested and show that the **Samsung Portable Handset FCC ID: A3LSCHW999** has been tested to comply with the requirements specified in §15.107 and §15.109 of the FCC Rules and Industry Canada Standard ICES-003.

FCC ID: A3LSCHW999		FCC Pt. 15B MEASUREMENT REPORT (CERTIFICATION)		Reviewed by: Quality Manager
Test Report S/N: 0Y1110171830.A3L	Test Dates: October 19 - 24, 2011	EUT Type: Portable Handset		Page 15 of 20